## Notice of References Cited Application/Control No. 10/550,529 Applicant(s)/Patent Under Reexamination HIRANO ET AL. Examiner OMONIYI A. OBAYANJU Art Unit Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0214928	11-2003	Chuah, Mooi Choo	370/336
*	В	US-2002/0126692	09-2002	Haartsen, Jacobus	370/450
*	С	US-7,280,518	10-2007	Montano et al.	370/338
*	D	US-7,154,877	12-2006	Le et al.	370/346
	Е	US-			
	F	US-			
	G	US-			
	Ι	US-			
	_	US-			
	٦	US-			
	K	US-			
	┙	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	C					
	V					
	w					
	х					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.